



Notic f References Cited

Application/Control No.

09/936,618

Examiner

Kathryn S. O'Malley

Applicant(s)/Patent Under
Reexamination
MAEDA ET AL.

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6491045	12-2002	Kamikawa et al.	134/102.3
	В	US-6412501	07-2002	Onoda et al.	134/95.2
	С	US-6247479	06-2001	Taniyama et al.	134/95.2
	D	US-6216709	04-2001	Fung et al.	134/25.4
	Ε	US-6152153	11-2000	Takase et al.	134/25.1
	F	US-6123900	09-2000	Vellutato	422/22
	G	US-5954911	09-1999	Bergman et al.	156/345.29
	Н	US-5951779	09-1999	Koyanagi et al.	134/2
	_	US-			
	٦	US-			
	к	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name ·	Classification
	N	JP-409213672-A	08-1997	Japan	NEC Yamaguchi Ltd.	·
	0					
	Р					
	Q	,				
	R					
	s					
	Т					

NON-PATENT DOCUMENTS

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